

Study on Photoconductivity in Semiconductor

施郁軒、范榮權

E-mail: 9509786@mail.dyu.edu.tw

ABSTRACT

The variation of conductance injected by the photon illumination in the semiconductor material are called the photoconductive effect. When the photon energy are absorbed by the semiconductor material, the electron in the valence band gotten enough energy can transit to the conduction band as if the photon energy larger than the energy gap. This behavior induced the excess carrier concentration which are contributed to the increasement of conductivity. The spectrum of photoconductivity in the different position of light spot on the semiconductor has been measured. It has been found that the characteristic of photoconductivity is dependent on the variation of spot position due to the property of carrier transport. According to the measurement of photoconductivity at different temperature, we obtained the energy gap depended on the temperature as following the Varshni 's equation. We also obtain the impurity center from the I-V curve experimental. From the thermal stimulated current measurement, the character peak at 50K due to the transition of carrier between the excited state to ground state, in the impurity center level. This impurity center energy are about 70meV which is agreement in the previous result. The absorption edge depended on the light radiated position is due to the not uniform concentration of carrier in the measurement of PC with different light spot position. From these result we can detected the optical property of semiconductor using these simple measurement.

Keywords : photoconductivity ; Hall effect ; I-V curve

Table of Contents

封面內頁 簽名頁 授權書	iii	中文摘要	
. iv 英文摘要		v 誌謝	
. vi 目錄		vii 圖目錄	
. ix 第一章 緒論	1	第二章 原理	
2.1 導帶與價帶	2	2.2 光電導原理	4
2.3 譜峰位置與溫度的關係	11	2.4 霍爾效應	12
2.5 載子濃度與分佈	17	第三章 實驗儀器與實驗步驟	
. 24		3.1 光電導量測	
3.2 降溫系統	25	3.3 Van der Pauw 霍爾量測	26
3.4 I-V 特性量測	27	3.5 電阻率量測	27
第四章 實驗數據與分析		4.1 光電導轉換	29
4.1 光電導轉換	29	4.2 光譜峰值位置與溫度的關係	31
4.3 Van der Pauw 量測	33	4.4 電壓電流特性量測	36
4.4 電壓電流特性量測	33	4.5 隨溫度變化的電阻率	38
4.5 隨溫度變化的電阻率	38	4.6 不同位置所量測的光電導	40
4.6 不同位置所量測的光電導	38	4.7 能帶分佈	
4.7 能帶分佈	43	4.8 載子分佈	43
4.8 載子分佈	43	4.9 光電壓量測	
4.9 光電壓量測	47	第五章 結論	49
第五章 結論	47	參考文獻	
參考文獻	50		

REFERENCES

- [1] 朱文章, 沈穎華, 半導體光電性質 (1995) [2] 梁文勝, 國立台灣大學, 物理學研究所, 碩士論文 (1989) [3] R. A. Smith " Semiconductors " 2nd Cambridge Press, (1978) [4] S. M. Sze " Physics of Semiconductor Devices " 2nd Bell Lab, (1981) [5] R. H. Bube, Photoelectronic properties of semiconductors, Cambridge University Press (1992) [6] Lake Shore, Hall Effect Electronic Transport Measurement System, (2001) [7] 施敏, 黃調元 譯, 半導體元件物理與製作技術(第二版), 國立交通大學出版社 (2002) [8] Y. P. Varshni, Physica 34, 149 (1967) [9] Birol Ozturk, Charles Blackledge, Bret N. Flanders, Reproducible interconnects assembled from gold nanorods, Applied Physics Letters, (2005) [10] J. C. Fan, Y. C. Wang, and I. S. Chen, Thermally stimulated current in self-organized InAs quantum dots, Applied Physics Letters, (2004) [11] Hirohiku Niu, Tetsuro Matsuda, Kenji Yamauchi, Munezo Takai, Lateral photovoltaic effect in nitrogen-implanted p-type silicon, Applied Physics Letters, (1972)